#### IN THE CLAIMS:

Please cancel claims 13-14 without prejudice.

1. (Currently Amended) An apparatus Apparatus designed to examine for examining a surface (9), comprising

a polarization analyser element or analyser (14) placed in the path of a light beam (17) reflected by the said surface[[,]]; characterized in that it comprises

a means for taking digital images (13) placed in the path of the beam reflected by the said surface downstream of the polarization analyser element[[,]]; and

a processing unit (15) capable of calculating the brightness and the intensity of a plurality of points of the said surface from pixels of at least two images of the said surface; wherein the apparatus does not contact the surface.

- 2. (Currently Amended) An apparatus Apparatus according to Claim 1, characterized in that comprises further comprising a source of polarized light capable of emitting a beam (16) incident on the said surface to be examined.
- 3. (Currently Amended) An apparatus Apparatus according to Claim 2, eharacterized in that wherein the light emanating from the said source is substantially isotropic.
- 4. (Currently Amended) An apparatus Apparatus according to Claim 2, characterized in that wherein the light emanating from the said source is substantially white.

- 5. (Currently Amended) An apparatus Apparatus according to Claim 2, characterized in that wherein the spectrum of the light emanating from the said source is substantially the same as the solar spectrum.
- 6. (Currently Amended) An apparatus Apparatus according to claim 1, eharacterized in that wherein the polarization analyser element comprises a means for transmitting the crossed polarization and a means for transmitting the parallel polarization, the said transmission means being alternatively active.
- 7. (Currently Amended) An apparatus Apparatus according to Claim 6, eharacterized in that wherein the polarization analyser element is rotating rotatable.
- 8. (Currently Amended) An apparatus Apparatus according to Claim 6, characterized in that the polarization analyser element further comprises an electrical switching means.
- 9. (Currently Amended) A process for the remote non-contact examination of a surface, comprising:
  - (i) analysing the polarization of a light beam reflected by the said surface;
  - (ii) taking digital images of particular polarizations of the said reflected beam; and
- (iii) calculating the brightness and the intensity of a plurality of points of the said surface from pixels of at least two images of the said surface.

- 10. (Currently Amended) A process Process according to Claim 9, in which wherein the said surface is uneven.
- 11. (Currently Amended) A process Process according to Claim 9, in which wherein the digital images are polychromic digital images.
- 12. (Amended) A process Process according to Claim 9, in which wherein the digital images are polychromic digital images are taken.

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- 13. (Cancelled)
- 14. (Cancelled)
- 15. (Currently Amended) An apparatus Apparatus designed to examine for examining a surface comprising

a polarization analyzer element or analyzer placed in the path of a light beam reflected by the said surface[[,]];

a means for taking digital images placed in the path of the beam reflected by the said surface downstream of the polarization analyzer element[[,]]; and

a processing unit capable of calculating the brightness and the intensity of a plurality of points of the said surface from pixels of at least two images of the said surface; wherein the apparatus does not contact the surface.

16. (Currently Amended) An apparatus Apparatus designed to examine for examining a surface comprising:

a polarisation analyser element or analyser element or analyser placed in the path of alight a light beam reflected by the said surface[[,]];

a camera for taking digital images placed in the path of the beam reflected by the [said] surface downstream of the polarization analyser element[[,]]; and

a processing unit capable of calculating the brightness and the intensity of plurality of points of the said surface from pixels of at least two images of the said surface; wherein the apparatus does not contact the surface.

- 17. (Currently Amended) An apparatus Apparatus according to Claim 15 or 16, eharacterized in that it comprises further comprising a source of polarized light capable of emitting a beam incident on the said surface to be examined.
- 18. (Currently Amended) An apparatus Apparatus according to Claim 17, eharacterized in that wherein the light emanating from the said source is substantially isotropic.
- 19. (Currently Amended) An apparatus Apparatus according to Claim 15 or 16, characterized in that wherein the light emanating from the said source is substantially white.
- 20. (Currently Amended) An apparatus according Apparatus to Claim 15 or 16, characterized in that wherein the spectrum of the light emanating from the said source is substantially the same as the solar spectrum.

- 21. (Currently Amended) An apparatus Apparatus according to Claim 15 or 16, characterized in that wherein the analyser comprises a means for transmitting the crossed polarization and a means for transmitting the parallel polarization, the said transmission means being alternatively active.
- 22. (Currently Amended) An apparatus Apparatus according to Claim 21, characterized in that wherein the analyser is rotating.
- 23. (Currently Amended) An appearatus Apparatus according to Claim 22 21, eharacterized in that wherein the analyser further comprises an electrical switching means.

Kindly add new claims 25 and 26 as follows:

- 24. (New) The process of Claim 9, wherein the process is performed by a computer.
- 25. (New) A computer-readable medium bearing a program code embodied thereon for performing the process of Claim 9.